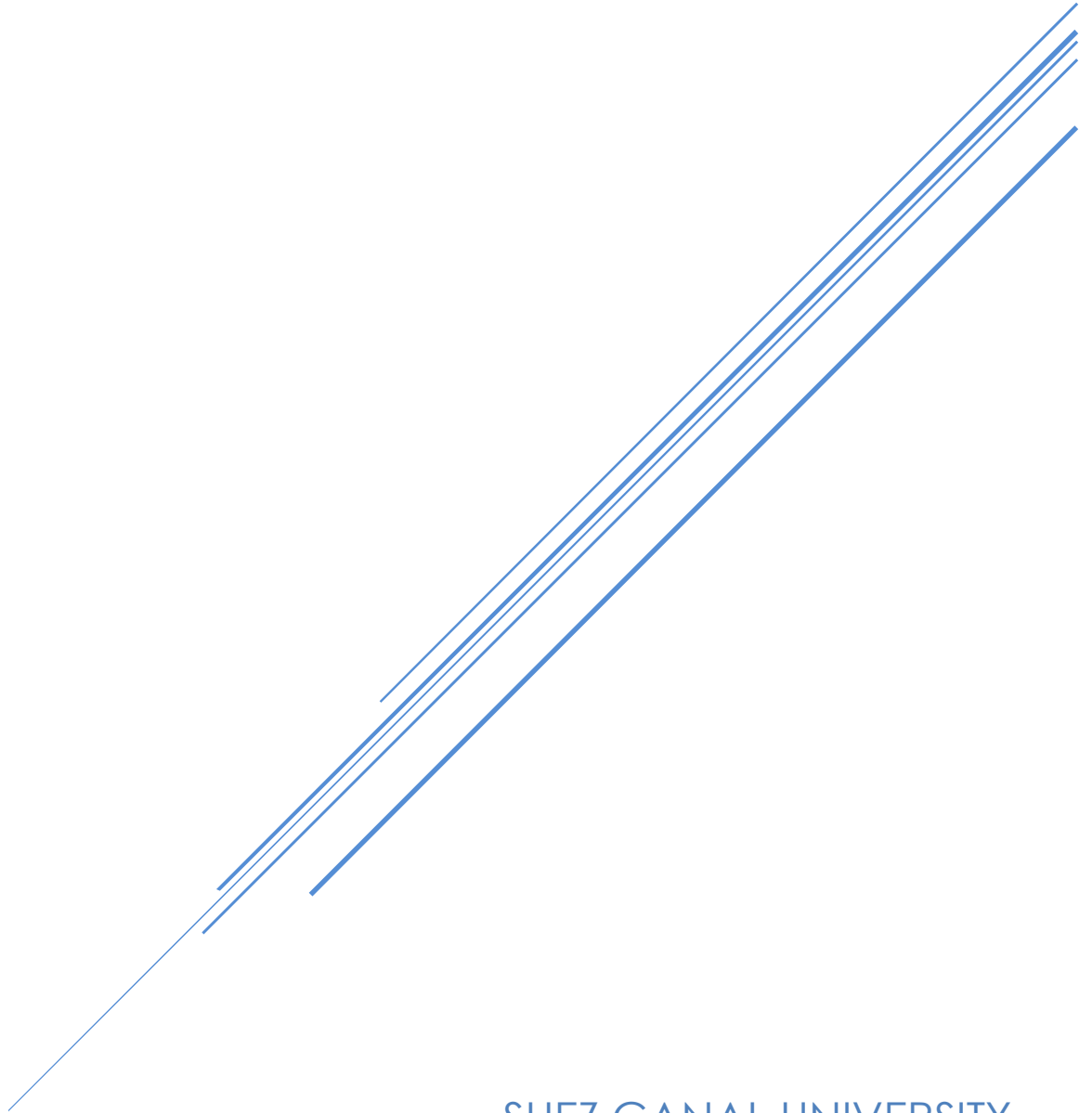


# INTEGRATED CIRCUITS 1

LAB01



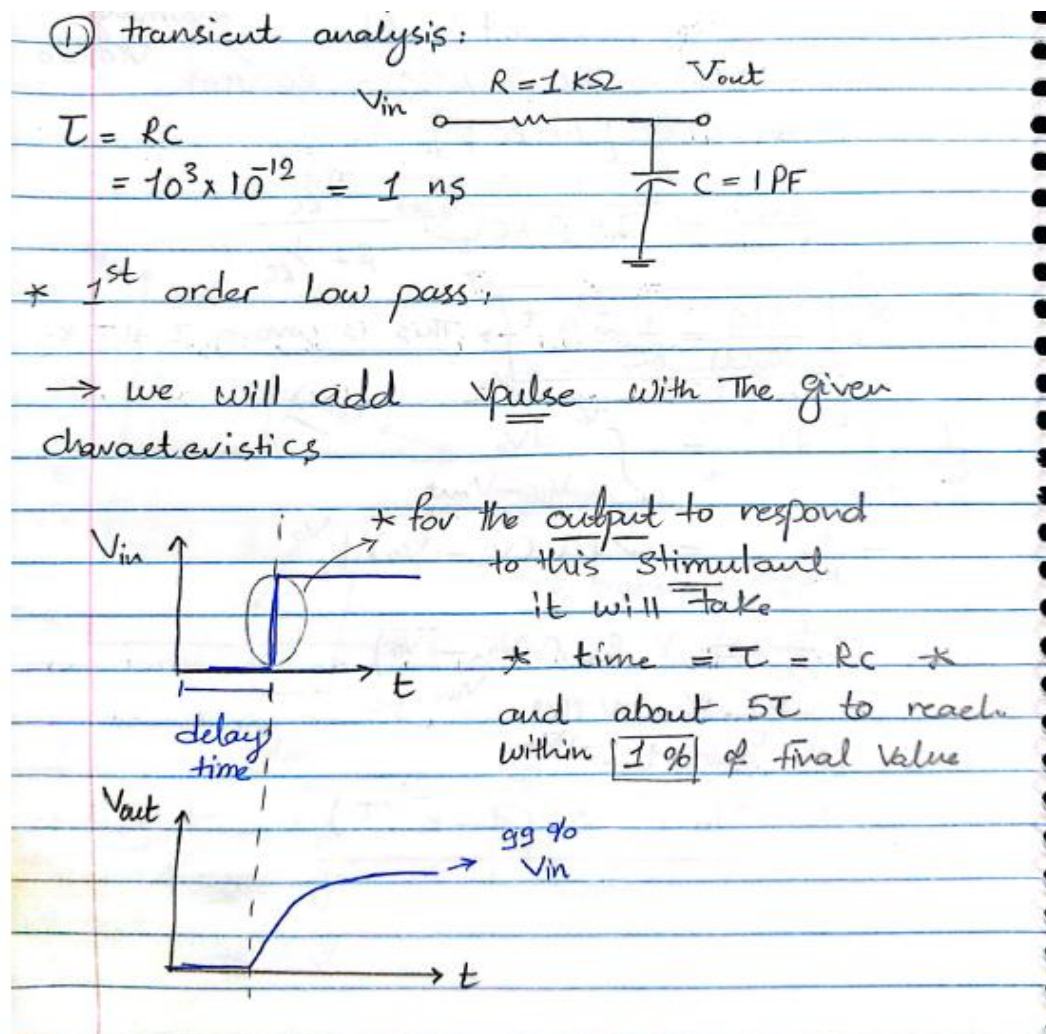
SUEZ CANAL UNIVERSITY

Yossef Ibrahim Abdel Aziz El Sayed Nada

## PART 1: LOW PASS FILTER SIMULATION:

### 1. Transient Analysis

- ✓ 1) Design a first order low pass filter that has  $R = 1k\Omega$  and 1ns time constant.
- ✓ 2) Apply a square wave input with  $T_{high} = \text{Pulse Width} = 10ns$ ,  $T_{clk} = \text{Period} = 20ns$ , and  $T_{rise} = T_{fall} = 100ps$ .
- ✓ 3) Report transient analysis results for two periods (use max time step =  $T_{clk}/100$ ).
- ✓ 4) Calculate rise and fall time (10% to 90%) using Cadence calculator expressions. Export the expressions to adexl.
- ✓ 5) Compare simulation with analytical results in a table.
- ✓ 6) Do parametric sweep for  $R = 1:1:5k\Omega$ . Report overlaid results. Comment on the results.



Some calculations:

$$\tau = 1 \text{ ns}$$

$$t_{\text{rise}} = t_{90\%} - t_{10\%}$$

$$V_0 = V_{\text{in}} (1 - e^{-t/\tau})$$

$$0.9 V_{\text{in}} = V_{\text{in}} (1 - e^{-t/\tau})$$

$$\times 0.1 = \times e^{-t/\tau}$$

$$- \ln 0.1 = -t/\tau \quad \therefore \quad T_{90\%} = 2.3 \tau = 2.3 \text{ ns}$$

at 10 %

$$\therefore 0.1 V_{\text{in}} = V_{\text{in}} (1 - e^{-t/\tau})$$

$$\times 0.9 = \times e^{-t/\tau}$$

$$T_{10\%} = 0.105 \tau \quad \therefore \quad T_{\text{rise}} = T_{90\%} - T_{10\%}$$

$$\therefore T_{\text{rise}} = T_{\text{fall}} = 2.3 \tau - 0.105 \tau = \boxed{2.195 \text{ ns}}$$

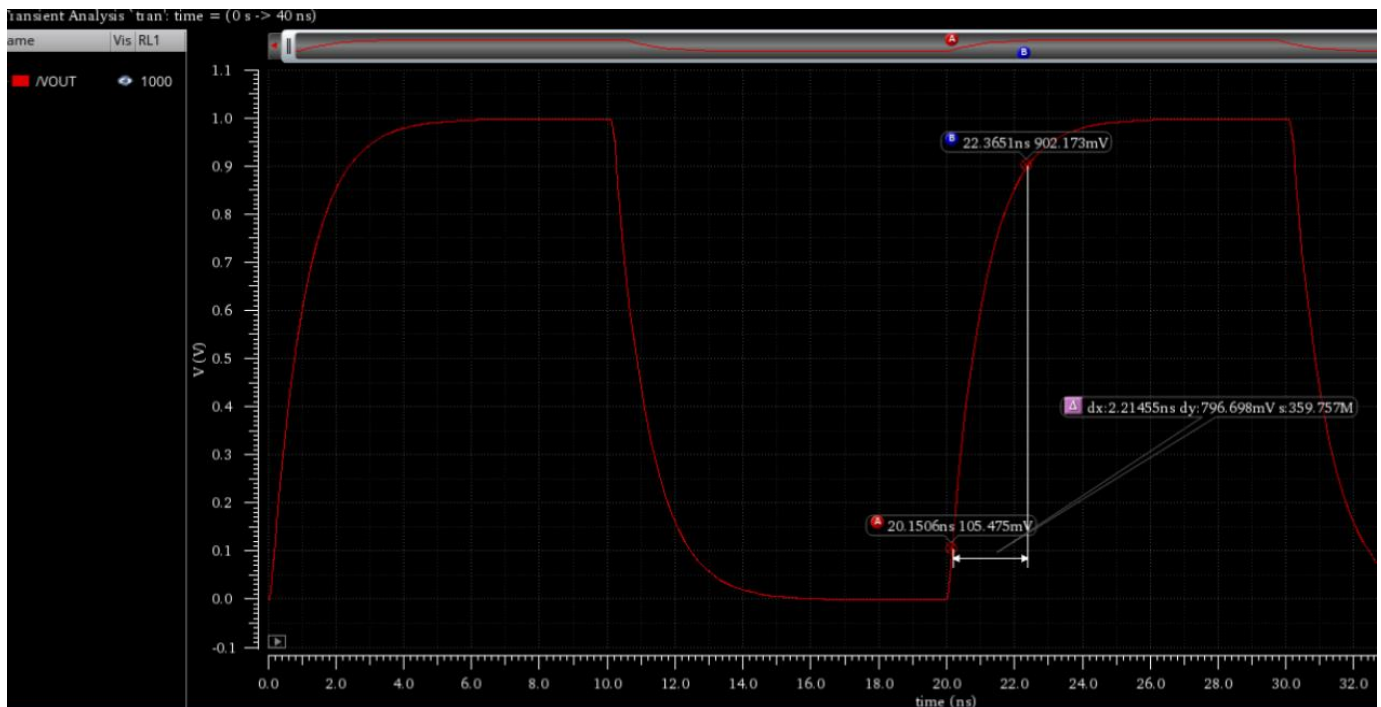
$$= 2.195 \tau$$

Using The Simulation we compared and found  
That  $T_{\text{rise}} = \text{fall time} = \underline{2.195 \text{ ns}}$

→ Also using The A-B Cursor on The Simulation  
we found That, rise time and fall time  
to be 2.2 ns

Tests  
IC1\_Lab1ab1:1  
Simulator spectre  
Analyses  
☒ tran 0.40n moderate  
Click to add analysis  
Design Variables  
k to add test  
Global Variables  
CL1 1p  
RL1 1k  
k to add variable  
Parameters  
Corners  
ocuments  
etup States  
liability Analyses  
ecks/Asserts  
Data History

Test	Output	Nominal	Spec
IC1_Lab1ab1:1	tpdr	2.195n	
IC1_Lab1ab1:1	tpdf	2.195n	
IC1_Lab1ab1:1	tpd	2.195n	



→ Parametric sweep  $\tau = RC$   
as  $R \uparrow$   $\tau \uparrow$

at  $R = 1k\Omega$   $\tau = 1nm$

$t_{rise} = t_{fall} = 2.195ns$

at  $R = 3k\Omega$   $\tau = 3nm$

$t_{rise} = t_{fall} = 2.195\tau = 2.195 \times 3$   
 $= 6.589ns$

at  $R = 5k\Omega$   $\tau$  is very large  
 $\tau = 5nm$

The  $V_{out}$  will not reach either 90%  
or 10% This will lead to evaluation  
error.

→ From the graph shown in the  
fig. as  $R_L$  increases  $\tau \uparrow$  and  
the time it takes to reach 90% or 10%  
at  $5k\Omega$  The  $V_{out}$  will not reach 90%  
or 10% leading to evaluation error.

Outputs Setup Run Preview Results Diagnostics				
Detail				
Point	Test	Output	Nominal	Spec
1	IC1_Lab:lab1:1	tpdf	2.195n	
1	IC1_Lab:lab1:1	tpd	2.195n	
1	IC1_Lab:lab1:1	/VOUT		
1	IC1_Lab:lab1:1	/VIN		
Parameters: RL=2k				
2	IC1_Lab:lab1:1	tpdr	4.391n	
2	IC1_Lab:lab1:1	tpdf	4.391n	
2	IC1_Lab:lab1:1	tpd	4.391n	
2	IC1_Lab:lab1:1	/VOUT		
2	IC1_Lab:lab1:1	/VIN		
Parameters: RL=3k				
3	IC1_Lab:lab1:1	tpdr	6.589n	
3	IC1_Lab:lab1:1	tpdf	6.589n	
3	IC1_Lab:lab1:1	tpd	6.589n	
3	IC1_Lab:lab1:1	/VOUT		
3	IC1_Lab:lab1:1	/VIN		
Parameters: RL=4k				
4	IC1_Lab:lab1:1	tpdr	8.787n	
4	IC1_Lab:lab1:1	tpdf	8.787n	
4	IC1_Lab:lab1:1	tpd	8.787n	
4	IC1_Lab:lab1:1	/VOUT		
4	IC1_Lab:lab1:1	/VIN		
Parameters: RL=5k				
5	IC1_Lab:lab1:1	tpdr	eval err	
5	IC1_Lab:lab1:1	tpdf	eval err	
5	IC1_Lab:lab1:1	tpd	eval err	
5	IC1_Lab:lab1:1	/VOUT		
5	IC1_Lab:lab1:1	/VIN		

Tests

IC1\_Lab:lab1:1

Simulator spectre

Analyses

☒ tran 0.40n moderate

Click to add analysis

Design Variables

Click to add test

Global Variables

CL1

1p

RL1

1k:1k:5k

Click to add variable

Parameters

Corners

Documents

Setup States

Reliability Analyses

Checks/Asserts

Data

History

Run Summary

1 Test

☒ 5 Point Sweeps

☒ 0 Corner

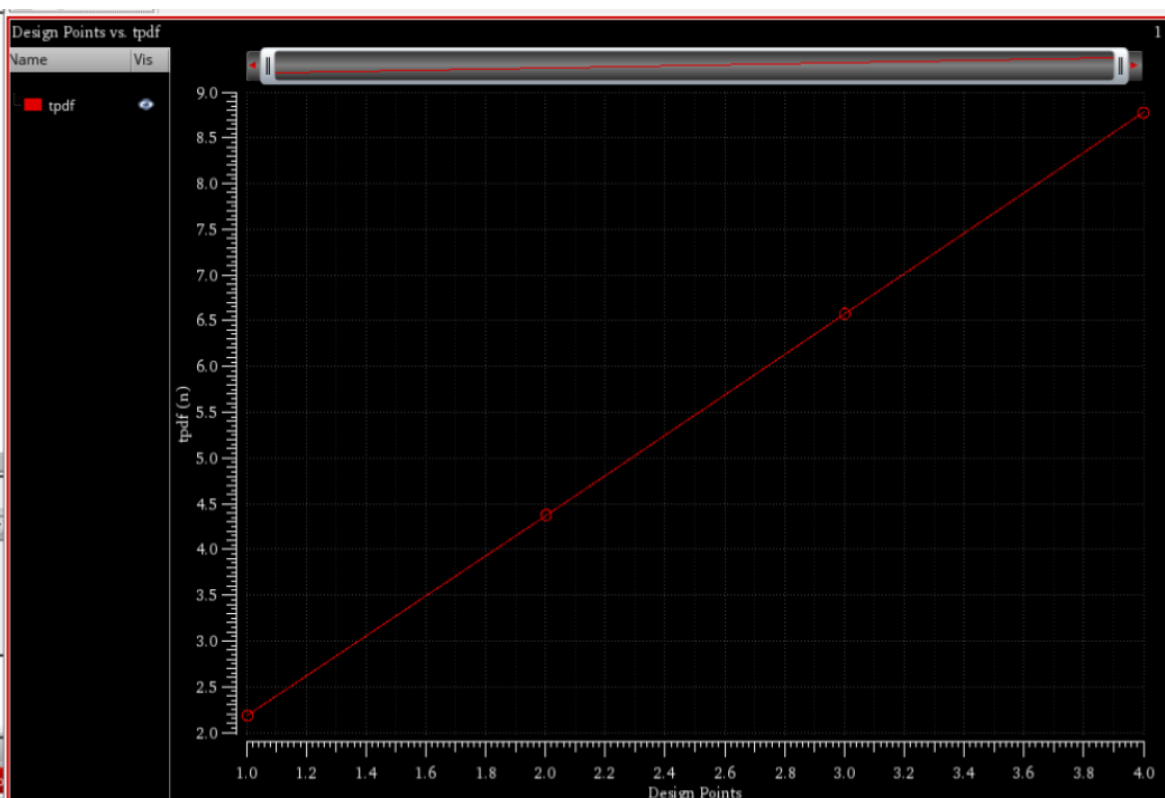
☒ Nominal Corner

History Item

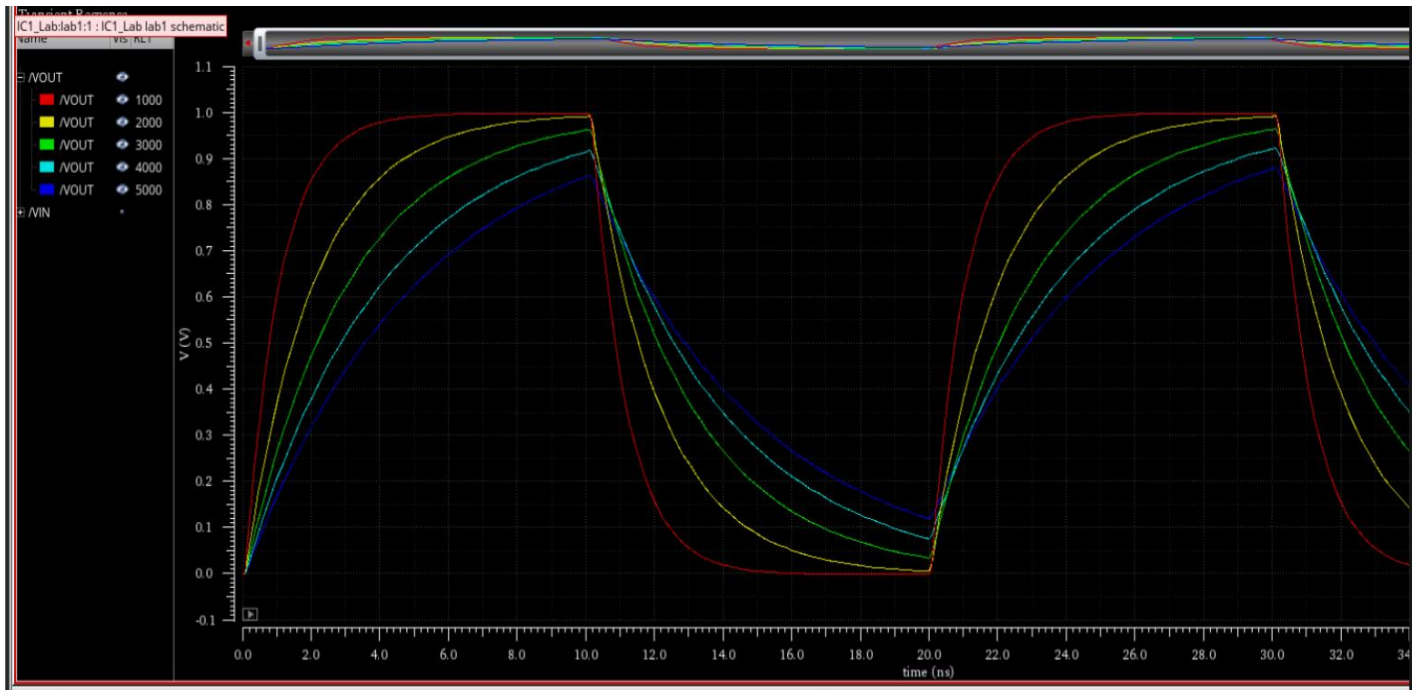
Status

Interactive.4

finished with error

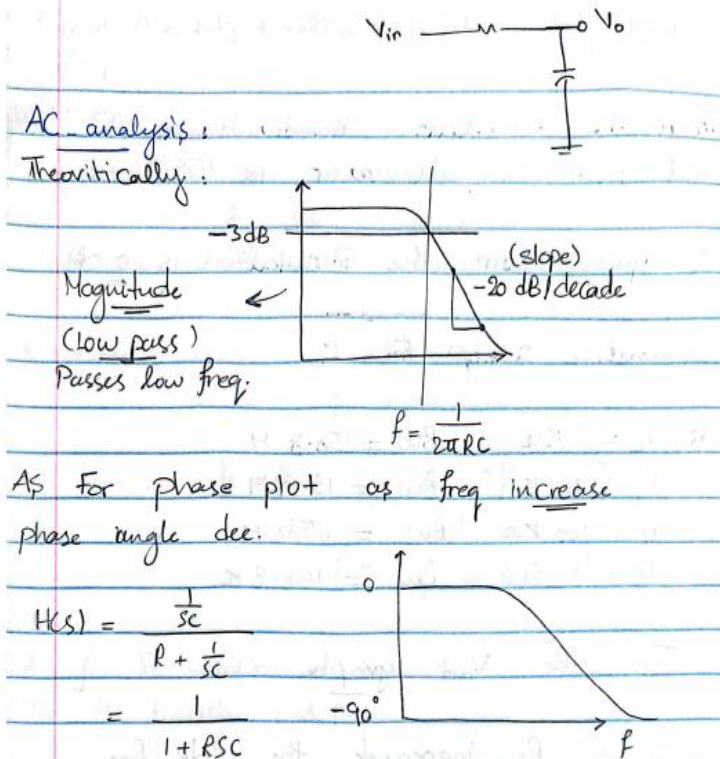






## 2. AC Analysis

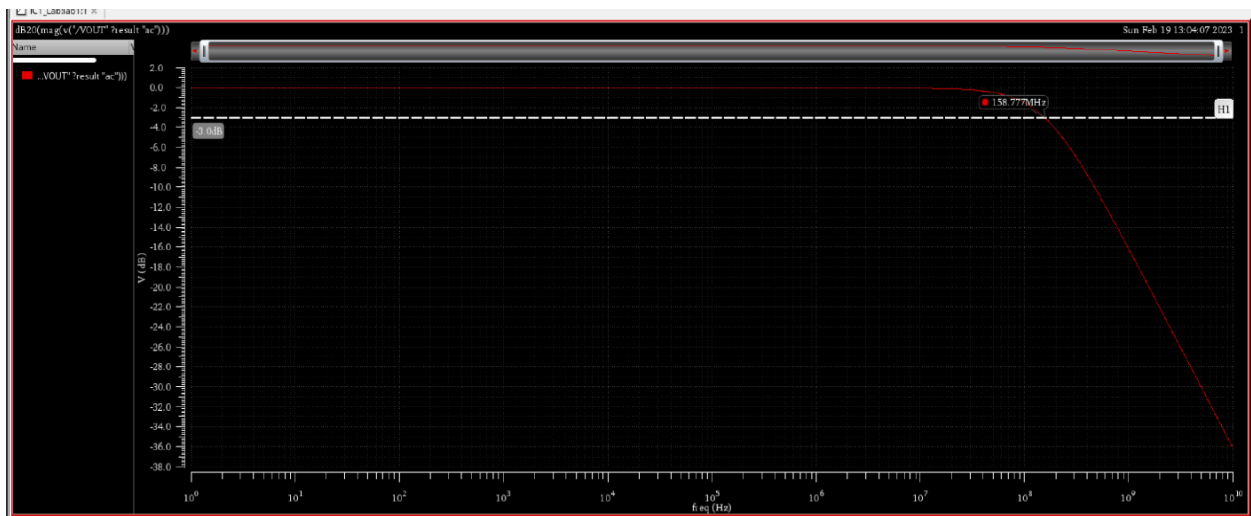
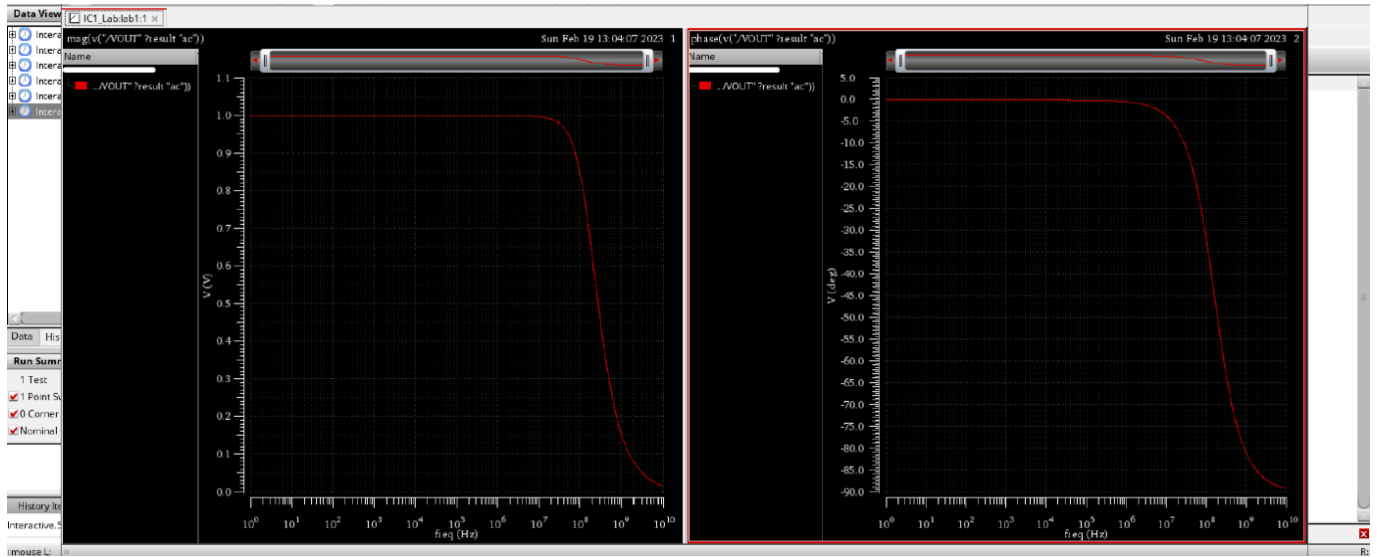
- 1) Report Bode Plot (magnitude and phase) for the previous LPF.
- 2) Calculate DC gain and 3dB bandwidth using Cadence calculator expressions. Export the expressions to adexl.
- 3) Compare simulation with analytical results in a table.
- 4) Do parametric sweep for  $R = 1, 10, 100, 1000 k\Omega$ . Report overlaid results. Comment on the results.



$$H(j\omega) = \frac{V_{ec}}{\frac{1}{RC} + j\omega} \rightarrow \text{as } f \uparrow \angle H(j\omega) \text{ decrease from } 0^\circ \text{ to } -90^\circ$$

DC gain at freq = zero  $\Rightarrow$  The capacitor is open circuit then  $V_{out} = V_{in}$   
 $gain = 1$

DC gain = 0 dB From The graph



No Parasitics/LDE

Single Run, Sweeps and Corners

Reference

Data View

lab1 x adex x

Outputs Setup Run Preview Results Diagnostics

Detail

Test	Output	Nominal	Spec	Weight	Pass/Fail
IC1_Lab1ab1:1	/VOUT				
IC1_Lab1ab1:1	mag(v("/VOUT" ?result "ac"))				
IC1_Lab1ab1:1	phase(v("/VOUT" ?result "ac"))				
IC1_Lab1ab1:1	BW	158.8M			
IC1_Lab1ab1:1	dB20(mag(v("/VOUT" ?result ...				

Run Summary

Back plot → right click → Direct plot → AC mag & phase

From the Simulation Bandwidth is 158.77 MHz  
and from the calculator is 158.8 MHz

DC gain from the simulation is 0 dB

parametric sweep for  $R_L$

at  $R_L = 1\text{ k}\Omega$  BW = 158.8 M  
 $R_L = 10\text{ k}\Omega$  BW = 15.88 M  
 $R_L = 100\text{ k}\Omega$  BW = 1.588 M  
 $R_L = 1\text{ M}\Omega$  BW = 158.8 K

From the  $V_{out}$  graph

as  $R_L$  increases the 3dB freq decrease.

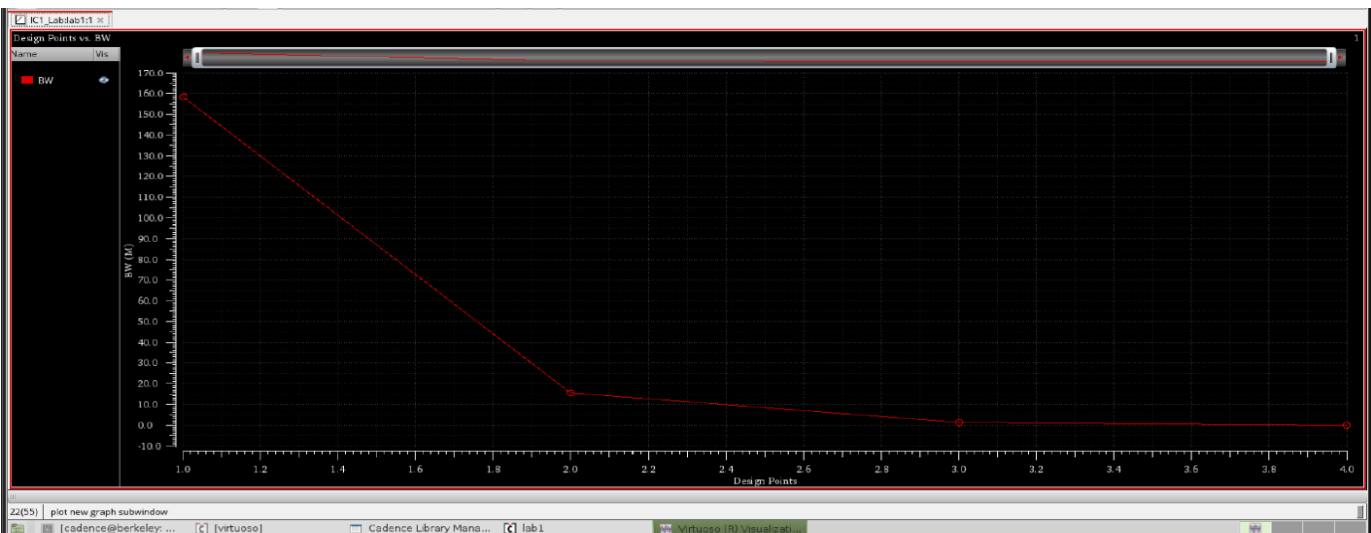
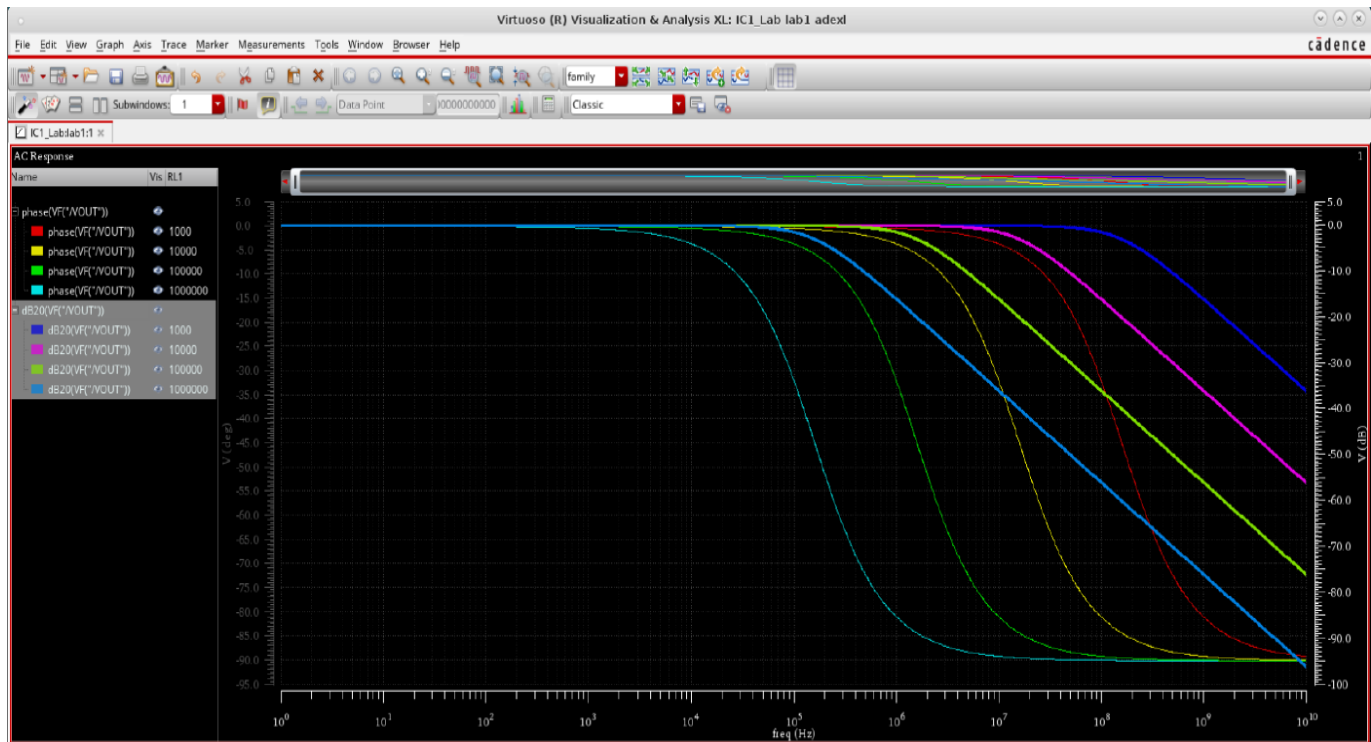
Bandwidth in this case  
 which can be seen from the graph

these results can also be validated from the Func.

$$H(s) = \frac{1}{1+R_sC}, \quad H(j\omega) = \frac{1}{1+R_L(j\omega)C}$$

Point	Test	Output	Nominal
Parameters: RL=1k			
1	IC1_Lablab1:1	VOUT	
1	IC1_Lablab1:1	mag(v("VOUT"?result "ac"))	
1	IC1_Lablab1:1	phase(v("VOUT"?result "ac"))	
1	IC1_Lablab1:1	BW	158.8M
1	IC1_Lablab1:1	dB20(mag(v("VOUT"?result ...	
Parameters: RL=10k			
2	IC1_Lablab1:1	VOUT	
2	IC1_Lablab1:1	mag(v("VOUT"?result "ac"))	
2	IC1_Lablab1:1	phase(v("VOUT"?result "ac"))	
2	IC1_Lablab1:1	BW	15.88M
2	IC1_Lablab1:1	dB20(mag(v("VOUT"?result ...	
Parameters: RL=100k			
3	IC1_Lablab1:1	VOUT	
3	IC1_Lablab1:1	mag(v("VOUT"?result "ac"))	
3	IC1_Lablab1:1	phase(v("VOUT"?result "ac"))	
3	IC1_Lablab1:1	BW	1.588M
3	IC1_Lablab1:1	dB20(mag(v("VOUT"?result ...	
Parameters: RL=1M			
4	IC1_Lablab1:1	VOUT	
4	IC1_Lablab1:1	mag(v("VOUT"?result "ac"))	
4	IC1_Lablab1:1	phase(v("VOUT"?result "ac"))	
4	IC1_Lablab1:1	BW	158.8k
4	IC1_Lablab1:1	dB20(mag(v("VOUT"?result ...	





### 3. [Optional] Pole Zero Analysis

- ✓ 1) Report pole zero analysis results.
- ✓ 2) Find the pole frequency and compare it with the bandwidth calculated from AC analysis.



results browser

## Pole-Zero analysis

no zeros were found  
according to simulation

→ no zeros were found

Pole at  $P_1 = -1.5915 \times 10^8$

However since:  $H(s) = \frac{1}{1 + RCs}$

∴  $s = -\frac{1}{RC} \rightarrow \text{pole}$

$P_1 = s = -\frac{1}{10^3 \times 10^{-12}} = -10^9$

∴  $f = \frac{-10^9}{2 \times \pi} = -1.59 \times 10^8 \text{ Hz}$

↓

Approximately  
The Same

Answer

As for The Comparison between  
The Bandwidth and pole

↓ ↓  
158.8 MHz, pole = -159.15 MHz

$f_{3dB} = \frac{1}{2\pi RC} \approx 159.15 \text{ MHz}$

Simulation ⇒ 158.8 MHz

↓

\* They are supposedly equal  
to each other.

$1 + RC(j\omega) = 0$

$RC(j\omega) = -1$

$j\omega = \frac{-1}{RC}$

$\omega = \frac{1}{RC}$   
 $f = \frac{1}{2\pi RC}$

.probe 0  
.measure 0  
save 0

Time for parsing: CPU = 0 s, elapsed = 15.439 ms.  
Time accumulated: CPU = 152 ms, elapsed = 157.483 ms.  
Peak resident memory used = 81.1 Mbytes.

### Pre-Simulation Summary

Warning from spectre.

WARNING (SPECTRE-16707): Only tran supports psfx1 format, result of other

\*\*\*\*\*

PZ Analysis 'pz'

\*\*\*\*\*

DC simulation time: CPU = 0 s, elapsed = 431.061 us.

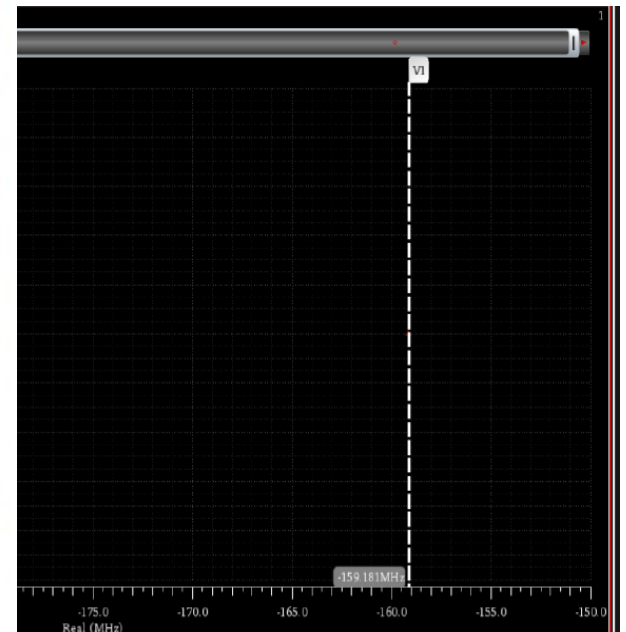
DC simulation time: CPU = 0 s, elapsed = 77.0092 us.

Poles (Hz)

	Real	Imaginary	Qfactor
1	-1.59155e+08	0.00000e+00	5.00000e-01

No zero is found

Accumulated DC solution time = 38.4519 ms.



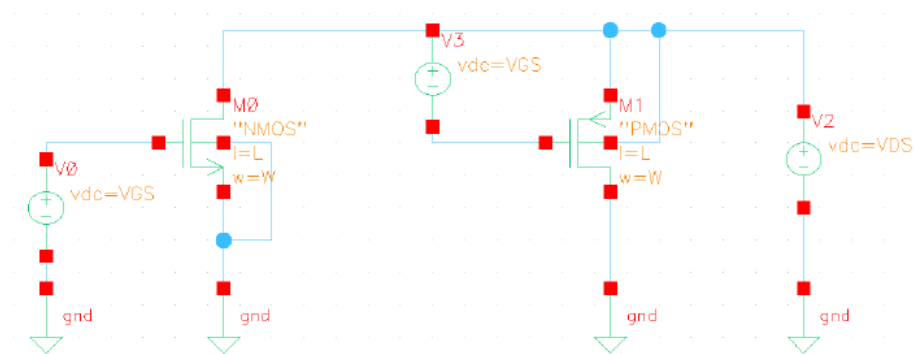
PZ Analysis 'pz'

Name | Vis | RL1

/poles 1000



## PART 2: MOSFET CHARACTERISTICS:

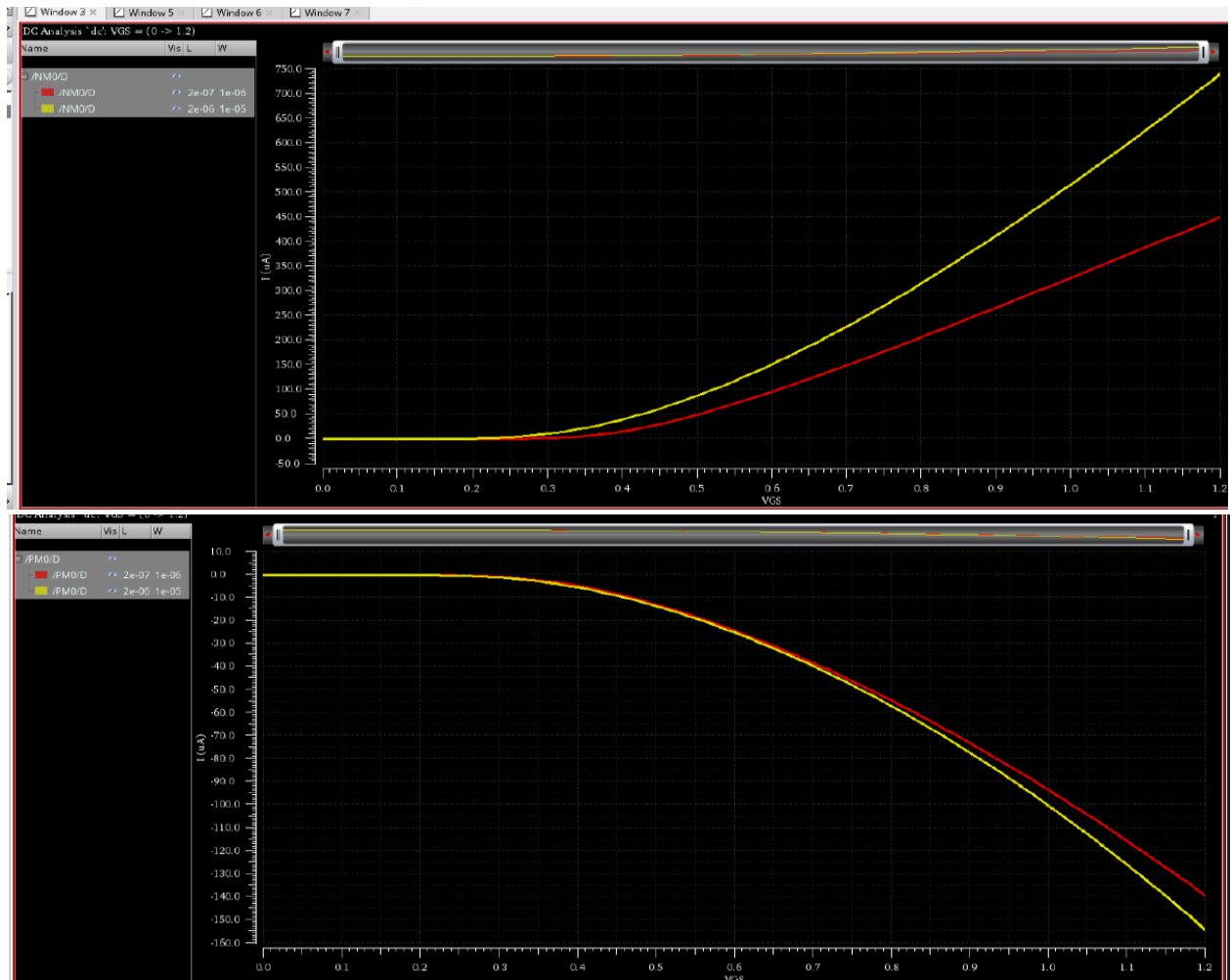


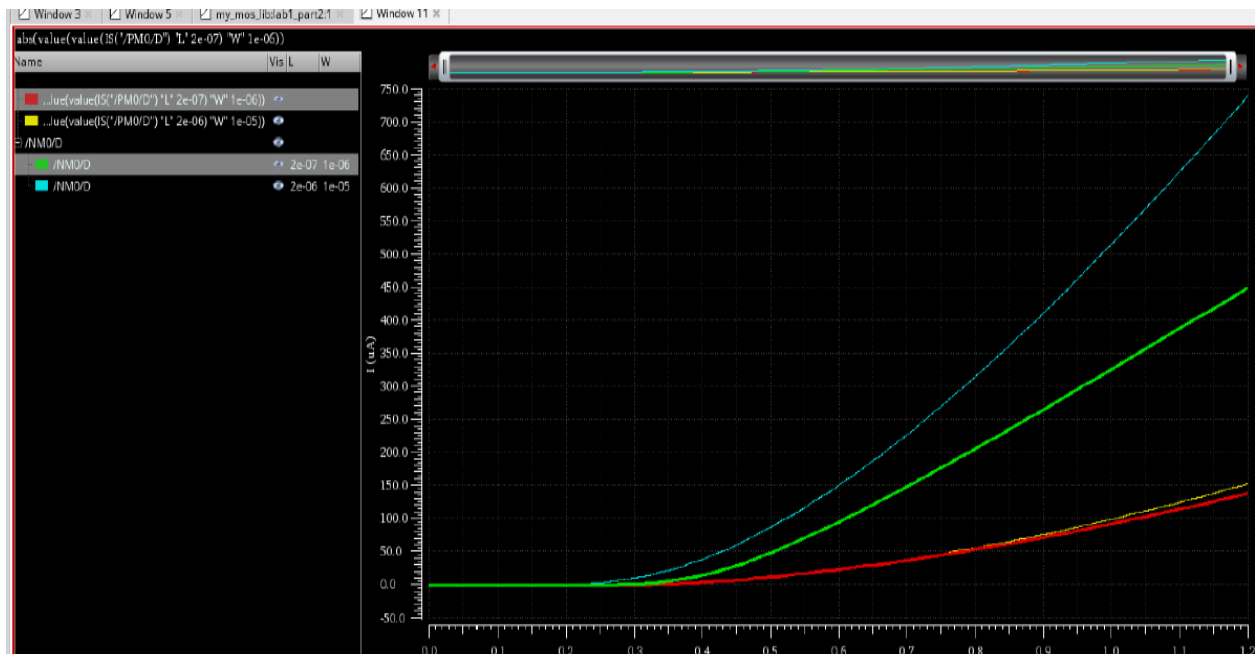
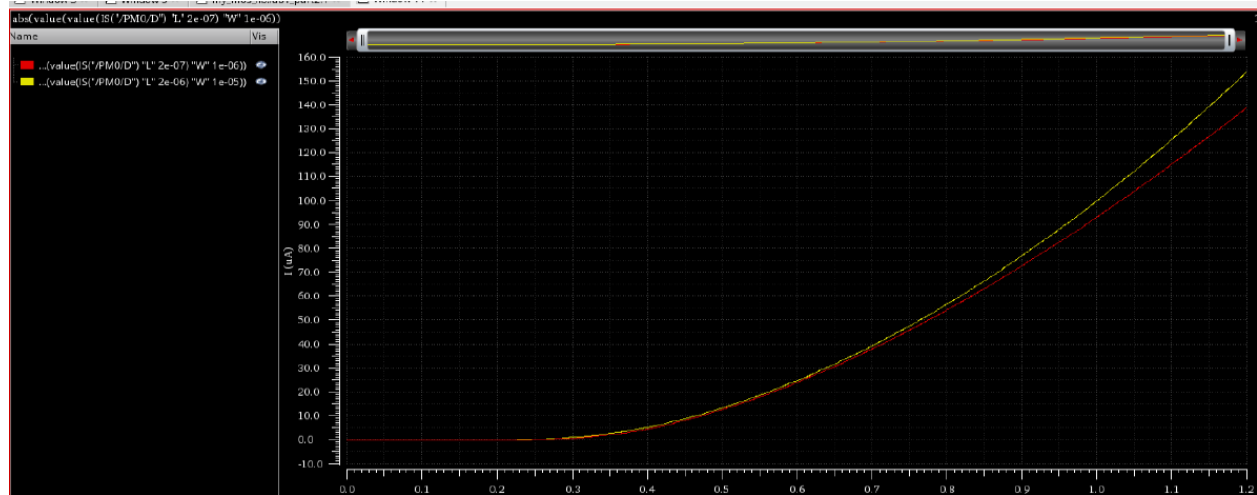
### 1. ID vs VGS

- Plot  $I_D - V_{GS}$  characteristics for NMOS and PMOS devices. Set  $V_{DS} = V_{DD}$ , and  $V_{GS} = 0:10m:V_{DD}$ . Use  $V_{DD} = 1.2V$  for 130nm technology and  $V_{DD} = 1.8V$  for 180nm technology. Plot the results overlaid for the following:

- Short channel device:  $W = 1\mu m$  and  $L = 200nm$
- Long channel device:  $W = 10\mu m$  and  $L = 2\mu m$ .

Hint: Set  $L$  as a parameter and set  $W = 5 \times L$





2) Comment on the differences between short channel and long channel results.

- Which one has higher current? Why?
- Is the relation linear or quadratic? Why?

3) Comment on the differences between NMOS and PMOS.

- Which one has higher current? Why?
- What is the ratio between NMOS and PMOS currents at  $V_{GS} = V_{DD}$ ?
- Which one is more affected by short channel effects?



→ From The graphs we find that,

2)

as for NMOS: long channel NMOS has higher current than short channel (as expected) That is because of the short channel effects (velocity saturation and mobility degradation)

→ long channel is quadratic while short channel is linear That's because of velocity sat.

pinch off sat. (in long channel) →  $I_D \propto V_{GS}^2$

Velocity sat. (in short channel) →  $I_D \propto V_{GS}$

PMOS has much less effects which we will discuss on the 2<sup>nd</sup> point.

3-

① NMOS has higher current because of the diff. in mobility Ratio electrons have higher mobility than holes

② at  $V_{GS} = V_{DD}$  The Ratio between at  $V_{DD}$  NMOS and PMOS is mobility Ratio, which

$$\text{is } \frac{739.3 \times 10^{-6}}{153.9 \times 10^{-6}} = 4.8$$

at Const. other Factors

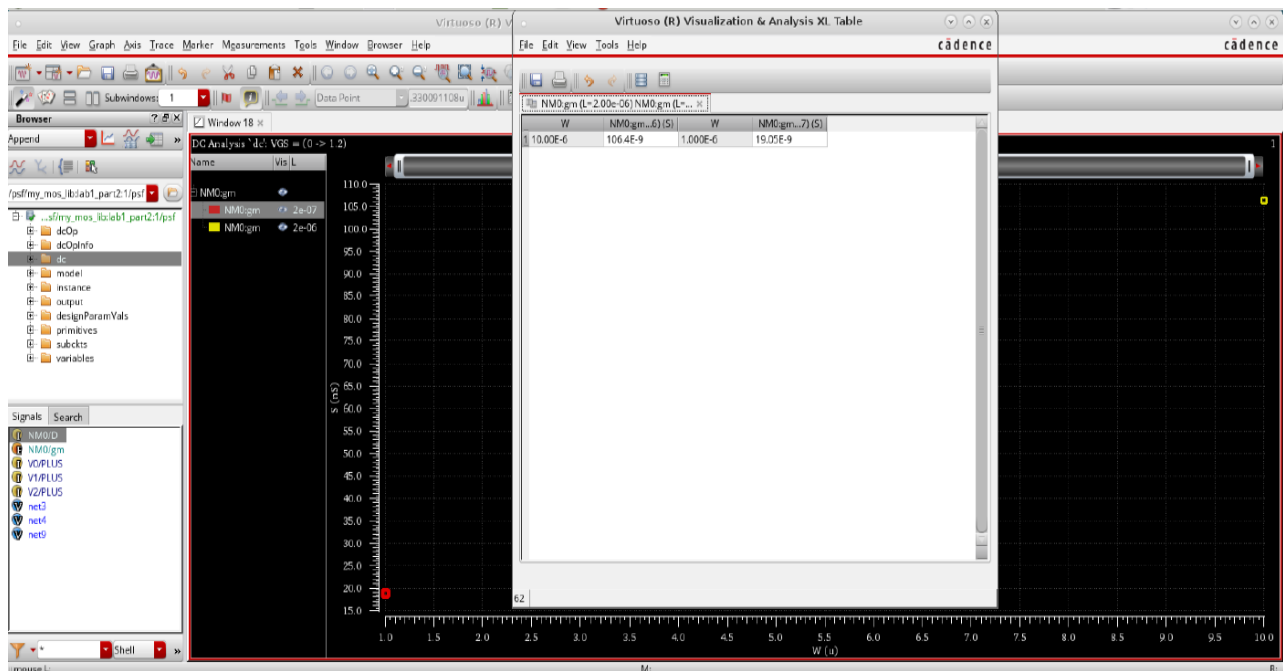
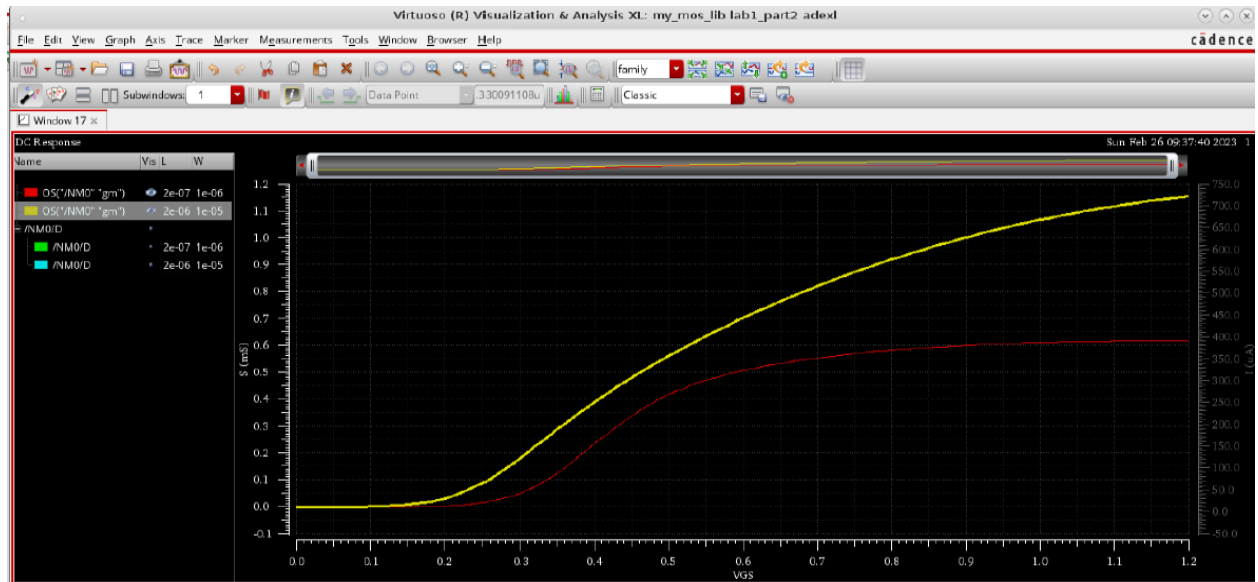
- NMOS is more affected by short channel effects because of the mobility Ratio, The mobility of holes is small when compared to electrons, so it doesn't saturate as fast as electrons (NMOS)



## ✓ $g_m$ vs $V_{GS}$

1) Plot  $g_m$  vs  $V_{GS}$  for NMOS device. Set  $V_{DS} = V_{DD}$ , and  $V_{GS} = 0:10m:V_{DD}$ . Plot the results overlaid for the following:

- Short channel device:  $W = 1\mu m$  and  $L = 200nm$
- Long channel device:  $W = 10\mu m$  and  $L = 2\mu m$ .



2) Comment on the differences between short channel and long channel results.

- Does  $g_m$  increase linearly? Why?
- Does  $g_m$  saturate? Why?

②  $g_m$  is the derivative of  $I_D$

$$g_m = \frac{\partial I_D}{\partial V_{GS}}$$

$g_m$  increases semi linearly in long channel  
That's because

$$I_D = \frac{1}{2} k_n V_{ov}^2$$

$$g_m = \frac{\partial I_D}{\partial V_{GS}} = k_n V_{ov} \quad g_m \propto V_{GS}$$

as for the short channel  $g_m$  will saturate much earlier that is due to velocity saturation where,

$$I_D = k_n \mu_{n, Cox} \frac{W}{L} \left( V_{ov} - \frac{V_{Dsat}}{2} \right) V_{Dsat}$$

$$I_D = C_{ox} W V_{sat} \left( V_{ov} - \frac{V_{Dsat}}{2} \right)$$

$$I_D \propto V_{GS}$$

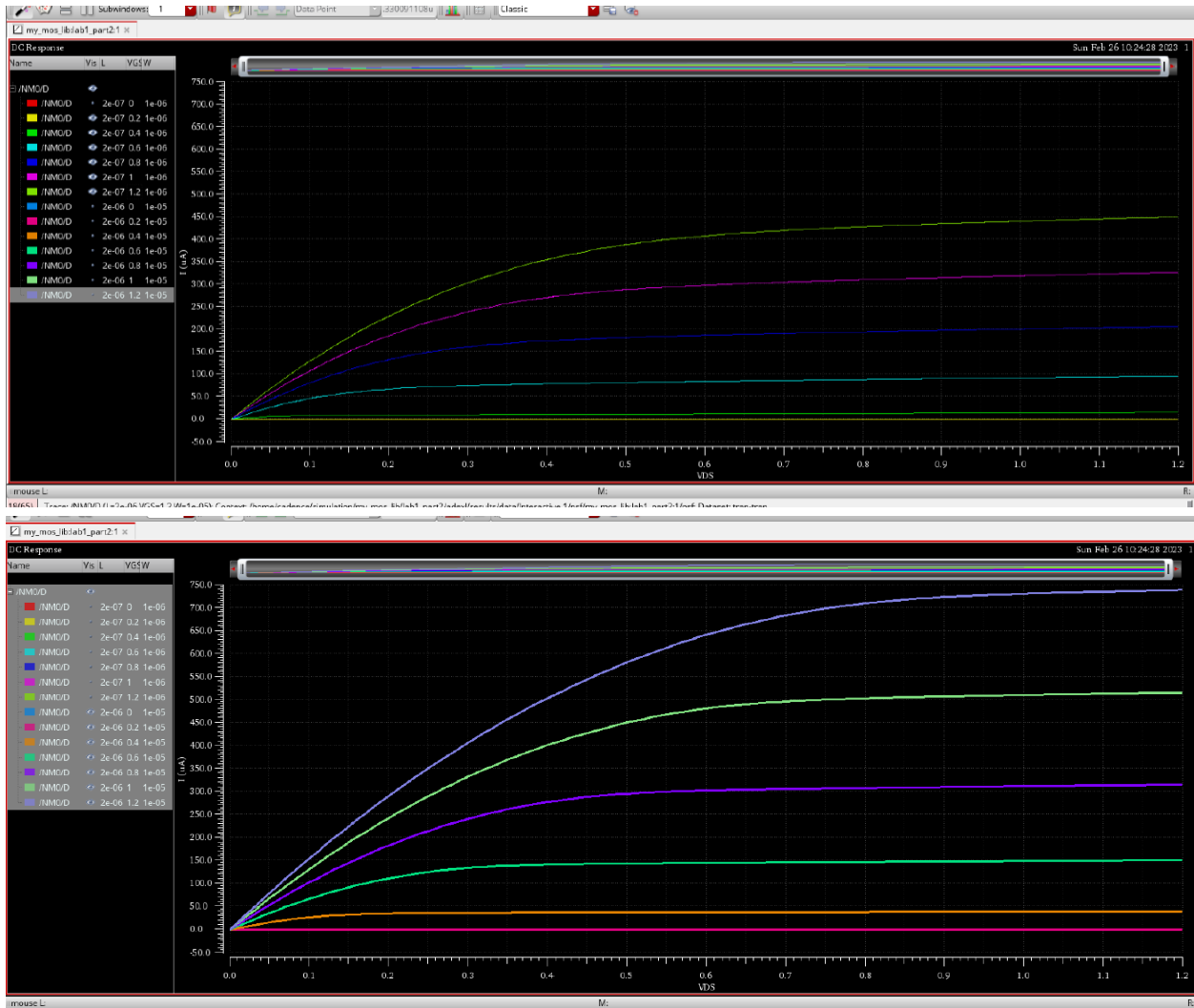
$\therefore g_m$  is const.

from the table you will find that  $g_m$  will saturate much earlier in case of short than long channel

### 3. ID vs VDS

1) Plot  $I_D - V_{DS}$  characteristics for NMOS device. Set  $V_{DS} = 0:10m:V_{DD}$ , and  $V_{GS} = 0:0.2:V_{DD}$  (nested sweep). Plot the results overlaid for the following:

- Short channel device:  $W = 1\mu m$  and  $L = 200nm$
- Long channel device:  $W = 10\mu m$  and  $L = 2\mu m$ .



#### ID vs VDS

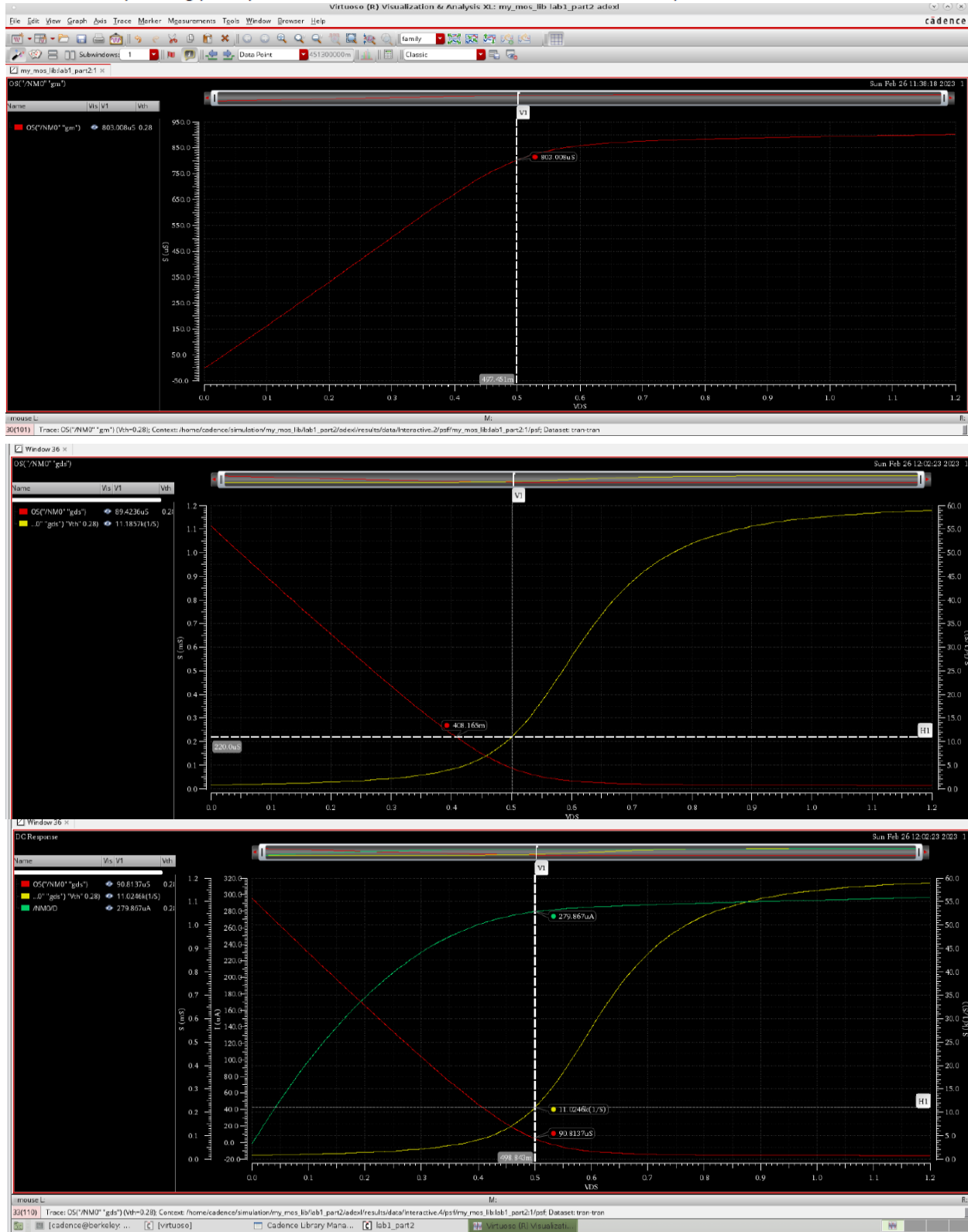
→ long channel has higher current than short channel. That is because of the short channel effects like velocity saturation and mobility degradation and Drain Induced Barrier Lowering as it decreases  $V_{th}$  thus  $V_{ov}$  inc. giving  $V_{gs}$  enough time to reach  $V_{DSsat}$  first and saturating at lower current.

Short  
→ long channel has higher slope in saturation region than long channel. That is because of the channel length modulation effect is more in case short than long channel because the dependence of the current on  $V_{DS}$  in short channel is larger than in long channel.

#### ✓ [Optional] $g_m$ and $r_o$ in Triode and Saturation

- 1) Plot  $g_m$  and  $r_o$  vs  $V_{DS}$  for NMOS device. Use  $W = 10\mu\text{m}$  and  $L = 2\mu\text{m}$ ,  $V_{DS} = 0:10\text{m}:V_{DD}$ , and  $V_{GS} \approx V_{TH} + 0.5\text{V}$ .

Hint: You can get an estimate of  $V_{TH}$  from the  $I_D$  vs  $V_{GS}$  characteristics, or you can print the operating point parameters of the transistor from DCOP/TRAN in Pyxis.





2) Comment on the variation of  $g_m$  vs  $V_{DS}$ .

- In the first part of the curve, is the relation linear? Why?
- Does  $g_m$  saturate? Why?
- Where do you want to operate the transistor for analog amplifier applications? Why?

4) from The graph  $I_D$  vs  $V_{GS}$  we find that  $V_{Th} = 0.28 \text{ V}$

2- The relation is linear in the first part of the curve, before  $V_{DS} = 0.5 \text{ V}$  the trans. was in the triode region where  $I_D \propto V_{DS}^2$ . Quadratic relation

$$I_D = k_n (V_{ov} V_{DS} - \frac{V_{DS}^2}{2})$$

Thus  $g_m$  is always derivative<sup>2</sup> of  $I_D$  then  $g_m$  is linear with  $V_{DS}$ .

• Then  $g_m$  saturates eventually because  $I_D$  gets in the saturation region

$$I_D = \frac{1}{2} k_n V_{ov}^2 (1 + \lambda V_{DS})$$

at some point the dependence of  $I_D$  on  $V_{DS}$  is semi-linear and thus  $g_m$  becomes constant

→ Saturation Region — as it can be used as VCCS, where  $I_D$  is dependent on  $V_{GS}$  mostly with a little effect from  $V_{DS}$ .

3) Comment on the variation of  $r_o$  vs  $V_{DS}$ .

- Does  $r_o$  saturate just after the transistor enters saturation similar to  $g_m$ ? Why?
- Does  $r_o$  increase if the transistor is biased more into saturation?
- Should we operate the transistor at the edge of saturation?
- Where do you want to operate the transistor for analog amplifier applications? Why?

3)  $r_o$  takes time before it saturates because of ELM,  $r_o$  increases with ELM until other short channel effects kick in  $r_o$  starts decreasing.

There is a little amount of  $V_{DS}$  dependence before it saturates

$\frac{1}{g_{ds}}$  in simulation

$r_o$  will ~~decrease~~ increase as we further go into saturation due to other channel length modulation  $V_{DS}$  dependence

Quadratic dependence on  $V_{DS}$

The Edge of Saturation will satisfy both Regions it might have properties of both.

Saturation Region as it's used as  $V_{CCS}$

↳ at The Region where  $r_o$  is almost constant before it starts decreasing. to give a stable gain

↳  $r_o$  will increase as we go further into saturation due to ELM until a point comes where The effect of other factors of short channel effects makes it decrease. ↳ DIBL, SCBE

Ultimately it depends on the application

at The Edge of saturation there, the eq. of The triode will hold and thus the current will depend on  $V_{DS}$  (Quadratic <sup>relation</sup> region) which will not be ideal if we want to use it as a  $V_{CCS}$ . (Thus No, we shouldn't)

The End